

“Complementi di Fisica”
Lecture 3



Livio Lanceri
Università di Trieste

Trieste, 03/06-10-2006

Course Outline - Reminder

- The physics of semiconductor devices: an introduction
 - Basic properties; energy bands, density of states
 - Equilibrium carrier concentration (“intrinsic”, “extrinsic”)
 - Carrier transport phenomena
 - Drift and Diffusion
 - Generation and Recombination
 - Continuity equations
- Quantum Mechanics: an introduction
- Advanced semiconductor fundamentals

- Lecture 2: intrinsic carrier concentrations...



Outline – Lecture 3

- “Intrinsic” (= pure) semiconductor *at equilibrium*
 - Equilibrium: computation of “carriers concentration”:
Concentration (carriers per unit volume) =
= sum (*integral*) over energy of:
(Available energy levels, per unit volume and per energy interval)
× (probability of filling the levels, per energy interval)
- “Extrinsic” (= doped) semiconductor *at equilibrium*
 - “donors” and “acceptors”: bond model
 - “donors” and “acceptors”: energy band model:
 - band diagrams
 - density of states
 - carriers concentration,
 - Fermi level



Intrinsic semiconductors

Fermi-Dirac distribution function

Intrinsic carriers concentration, Fermi level

Fermi probability distribution function

- Electrons fill up available states following the Pauli principle (two electrons with opposite spin for each level)
- Probability distribution function (Fermi-Dirac, more details in the second part of the course):

$$F(E) = \frac{1}{1 + e^{(E-E_F)/kT}}$$

$$E = E_F \Rightarrow F(E) = 1/2$$

$$E \rightarrow \infty \Rightarrow F(E) \rightarrow 0$$

$$E \rightarrow -\infty \Rightarrow F(E) \rightarrow 1$$

$$k = 8.617 \times 10^{-5} \text{ eV/K} \quad \text{Boltzmann constant, } T \text{ temperature (K)}$$

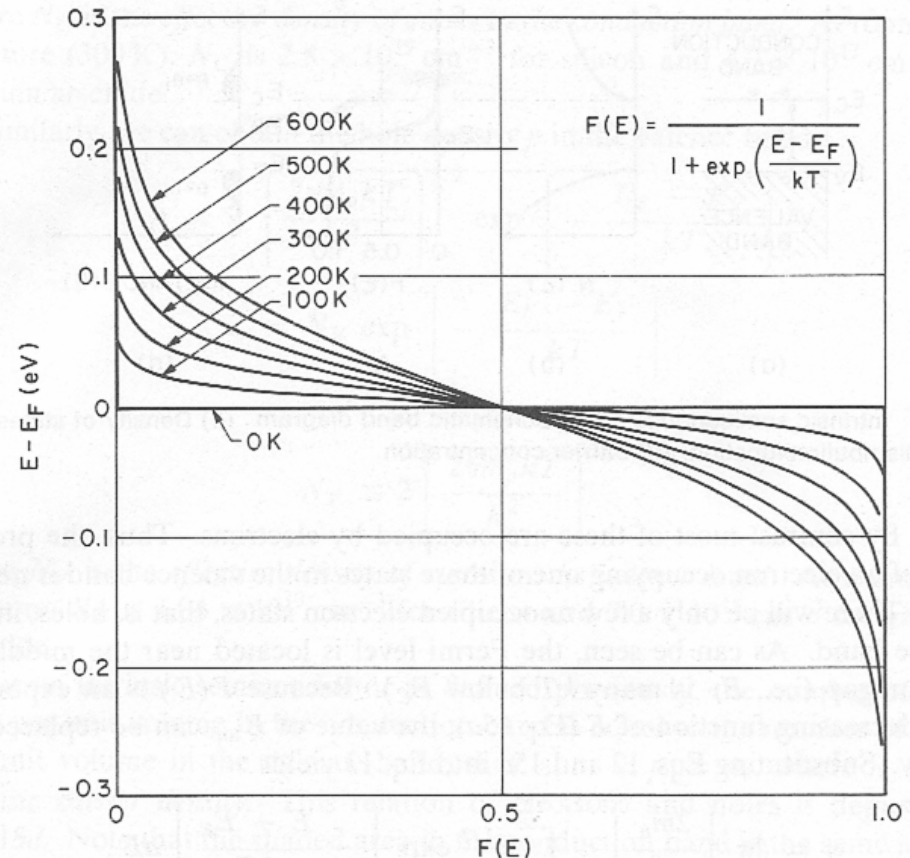
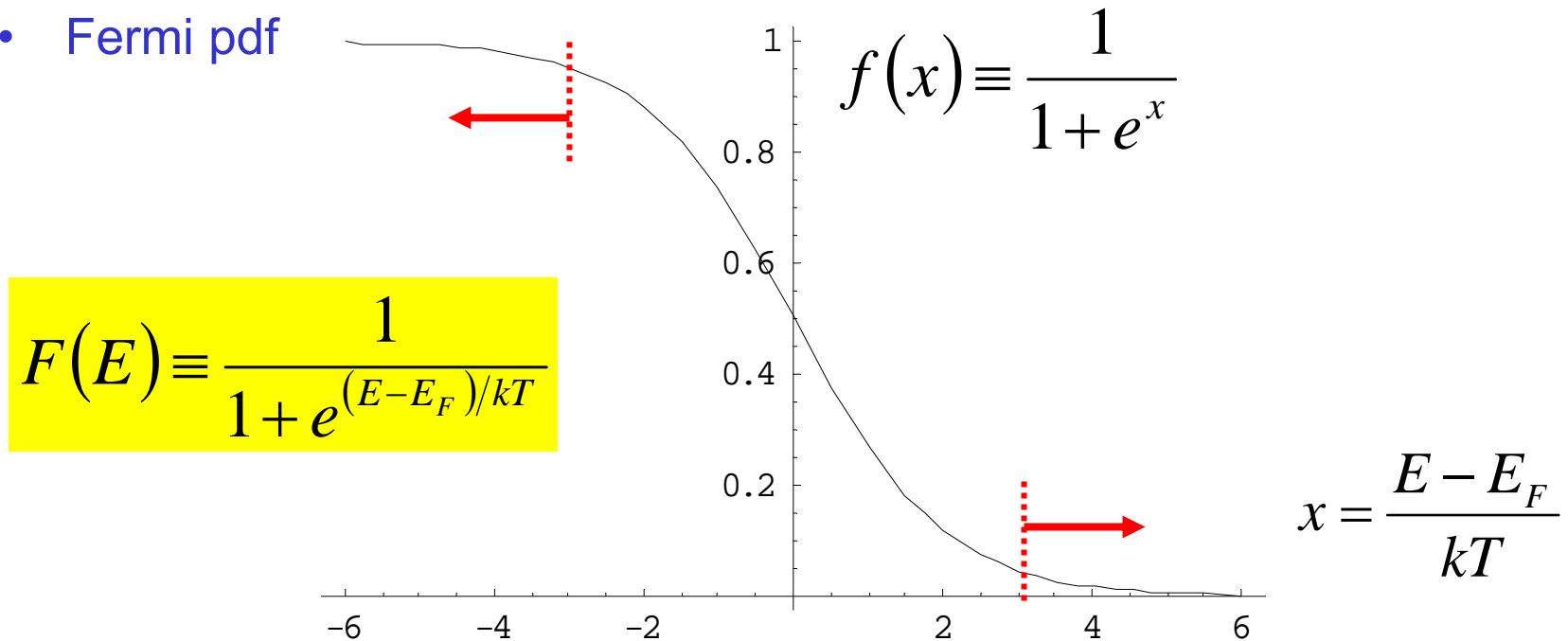


Fig. 14 Fermi distribution function $F(E)$ versus $(E - E_F)$ for various temperatures.

Fermi pdf: approximate expressions

- Fermi pdf



$$F(E) \equiv \frac{1}{1 + e^{(E - E_F)/kT}}$$

- approximate expressions for energies far enough from E_F :

$$E - E_F > 3kT \Rightarrow F(E) \approx e^{-(E - E_F)/kT} \quad \left(x > 3 \Rightarrow \frac{1}{1 + e^x} \approx e^{-x} \right)$$

$$E - E_F < -3kT \Rightarrow F(E) \approx 1 - e^{-(E_F - E)/kT} \quad \left(x < -3 \Rightarrow \frac{1}{1 + e^x} \approx 1 - e^x \right)$$



Fermi pdf: approximate expressions

- Simpler expressions for energies far enough from E_F :

$$F(E) \cong e^{-(E-E_F)/kT} \quad \text{for } E - E_F > 3kT$$

$$F(E) \cong 1 - e^{-(E_F-E)/kT} \quad \text{for } E - E_F < -3kT$$



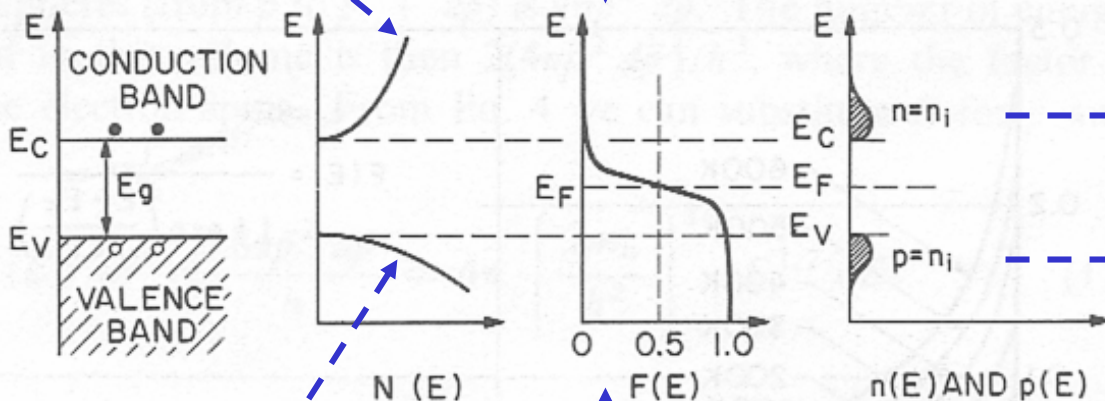
Intrinsic carrier concentrations

$$g_C(E) = \frac{m_n^* \sqrt{2m_n^*(E - E_C)}}{\pi^2 \hbar^3}$$

Effective density of states
In the conduction band

$$F(E) \cong e^{-(E - E_F)/kT}$$

$$N_C \equiv 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2}$$



$$n \cong N_C e^{-(E_F - E_C)/kT}$$

$$p \cong N_V e^{-(E_V - E_F)/kT}$$

$$1 - F(E) \cong e^{-(E_F - E)/kT}$$

$$N_V \equiv 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2}$$

Effective density of states
In the valence band

$$g_V(E) = \frac{m_p^* \sqrt{2m_p^*(E_V - E)}}{\pi^2 \hbar^3}$$

Exercise 2.1 Integrate $g(E)F(E)$ to obtain n and p



Intrinsic electron concentration n

- Explicit computation for electrons:

$$\begin{aligned}
 n &= \int_{E_C}^{\infty} g_C(E) F(E) dE = \\
 &= 4\pi \left(\frac{2m_n^*}{h^2} \right)^{3/2} \int_{E_C}^{\infty} (E - E_C)^{1/2} e^{-(E-E_F)/kT} dE = \\
 &= 4\pi \left(\frac{2m_n^*}{h^2} \right)^{3/2} \int_0^{\infty} E'^{1/2} e^{-(E'+E_C-E_F)/kT} dE' = \\
 &= 4\pi \left(\frac{2m_n^*}{h^2} \right)^{3/2} (kT)^{3/2} \exp\left(-\frac{E_C - E_F}{kT}\right) \int_0^{\infty} x^{1/2} e^{-x} dx = \\
 &= 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2} \exp\left(-\frac{E_C - E_F}{kT}\right)
 \end{aligned}$$

$g_C(E)$ state density
 Fermi f. for $E - E_F > 3kT$
 $F(E) \approx e^{-(E-E_F)/kT}$
 change variables:
 $E' = E - E_C \quad dE' = dE$
 $x = \frac{E'}{kT} \quad dE' = kT dx$

$$\int_0^{\infty} x^{1/2} e^{-x} dx = \frac{\sqrt{\pi}}{2}$$



Intrinsic hole concentration p

- Explicit computation for holes:

$$\begin{aligned}
 p &= \int_{-\infty}^{E_V} g_V(E)(1-F(E))dE = \\
 &= 4\pi \left(\frac{2m_p^*}{h^2} \right)^{3/2} \int_{-\infty}^{E_V} (E_V - E)^{1/2} e^{-(E_F - E)/kT} dE = \\
 &= 4\pi \left(\frac{2m_p^*}{h^2} \right)^{3/2} \int_0^{\infty} E'^{1/2} e^{-(E' + E_F - E_V)/kT} dE' = \\
 &= 4\pi \left(\frac{2m_p^*}{h^2} \right)^{3/2} (kT)^{3/2} \exp\left(-\frac{E_F - E_V}{kT}\right) \int_0^{\infty} x^{1/2} e^{-x} dx = \\
 &= 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2} \exp\left(-\frac{E_F - E_V}{kT}\right)
 \end{aligned}$$

$g_V(E)$ state density
 $1 - F(E)$ for $E - E_F < -3kT$
 $1 - F(E) \approx e^{-(E_F - E)/kT}$
 change variables:
 $E' = E_V - E \quad dE' = -dE$
 $x = \frac{E'}{kT} \quad dE' = kT dx$

$$\int_0^{\infty} x^{1/2} e^{-x} dx = \frac{\sqrt{\pi}}{2}$$



Intrinsic Fermi level and carrier density

“Effective density of states”
In the conduction band

$$N_C \equiv 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2} \cong 2.8 \times 10^{19} \text{ cm}^{-3} \text{ (Si)},$$

$$[T \approx 300\text{K}] \quad \cong 4.7 \times 10^{17} \text{ cm}^{-3} \text{ (GaAs)}$$

“Effective density of states”
In the valence band

$$N_V \equiv 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2} \cong 1.04 \times 10^{19} \text{ cm}^{-3} \text{ (Si)}$$

$$[T \approx 300\text{K}] \quad \cong 7.0 \times 10^{18} \text{ cm}^{-3} \text{ (GaAs)}$$

$$n \cong N_C e^{-(E_F - E_C)/kT}$$

$$p \cong N_V e^{-(E_V - E_F)/kT}$$

For an intrinsic semiconductor:

$$n = p = n_i$$

Intrinsic carrier density

$$n = p \Rightarrow E_i = E_F = \frac{E_C + E_V}{2} + \frac{kT}{2} \ln \left(\frac{N_V}{N_C} \right) = \frac{E_C + E_V}{2} + \frac{3kT}{4} \ln \left(\frac{m_p}{m_n} \right) \Rightarrow E_i \cong \frac{E_C + E_V}{2}$$

“mass action law”: at thermal equilibrium:

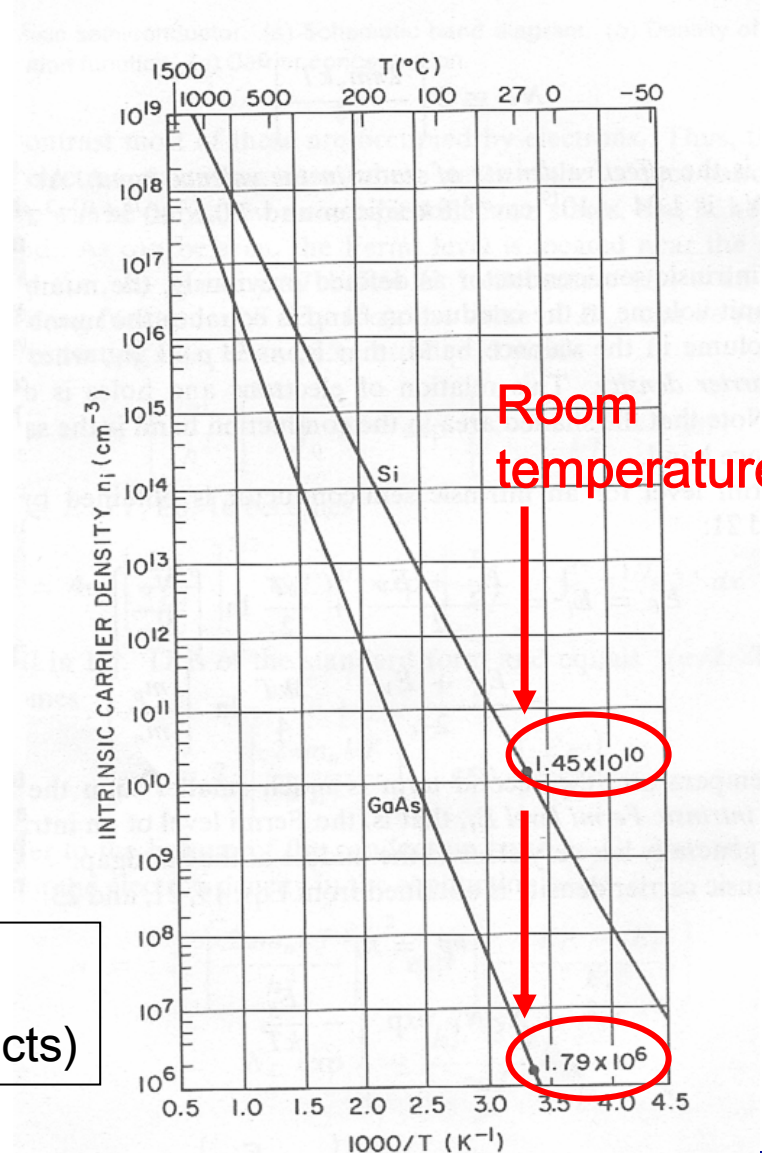
$$np = n_i^2 = N_C N_V e^{-E_g/kT} \Rightarrow n_i = \sqrt{N_C N_V} e^{-E_g/2kT}$$

Intrinsic Fermi level



Intrinsic carrier densities

- Temperature dependence
 - increase with temperature
 - smaller with larger E_g
- Caveats:
 - Pure Si: very low conductivity: $\sigma \approx 10^{-6} (\Omega \text{ cm})^{-1}$ at $T \approx 300\text{K}$
 - However, in practice dominated by defects (Kowalski method: typically $10^{11}/\text{cm}^2$)
 $\Rightarrow \sigma \approx 10^{-5} (\Omega \text{ cm})^{-1}$
 - Doping is needed in practice, to control conductivity!



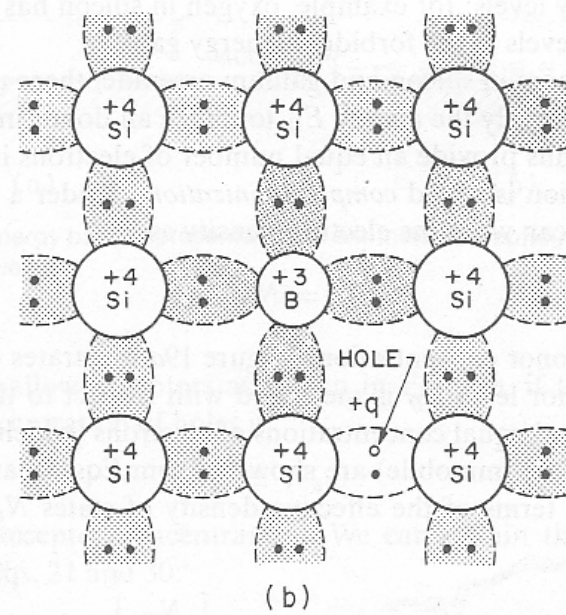
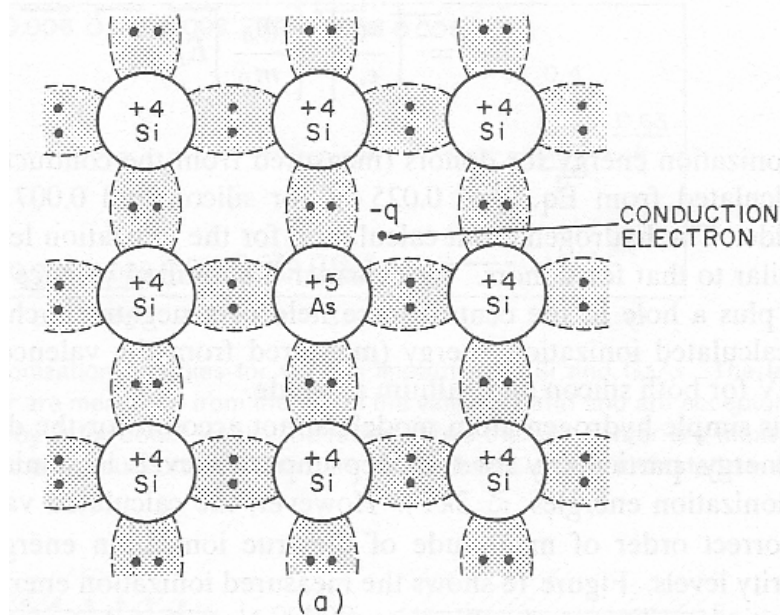
Exercise 2.2 Estimate orders of magnitude for the conductivity of Si (pure and with realistic defects)



“extrinsic” (doped) semiconductors

Donors and acceptors

- Bond model:

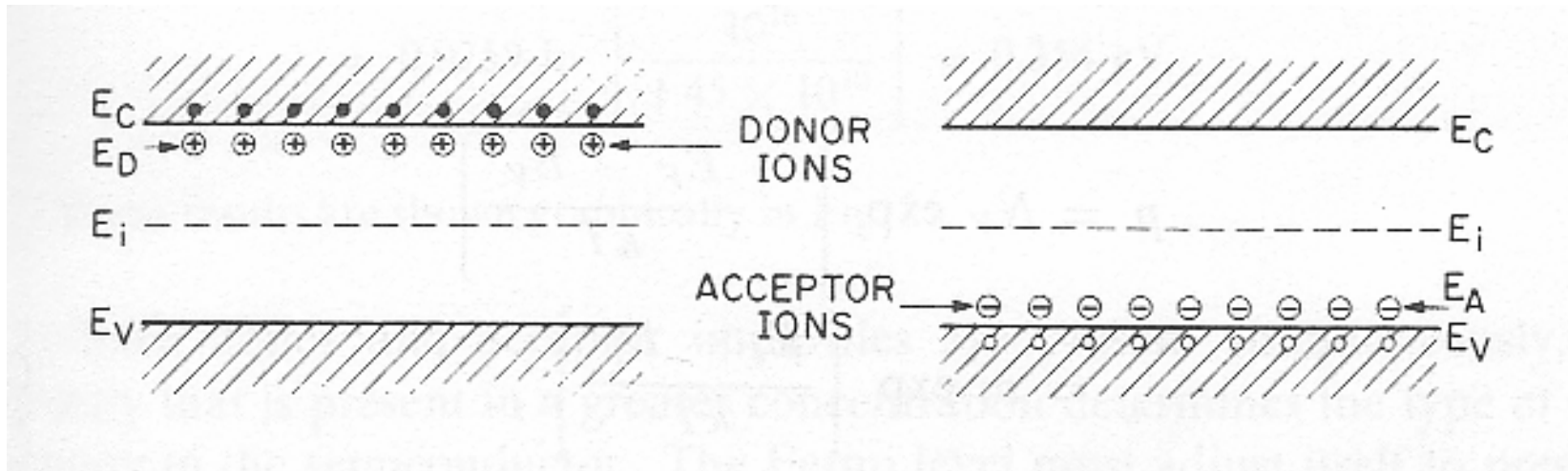


n-type Si with “*donor*” impurities
(As: 5 valence electrons)
The fifth electron is “*donated*”
to the conduction band;
the remaining positive ion is *fixed*

p-type Si with “*acceptor*” impurities
(B: 3 valence electrons)
An additional electron is “*accepted*”
from the valence band, creating a hole
The resulting negative ion is *fixed*

Donors and acceptors

- Energy band model



n-type Si with “*donor*” energy levels very close to the conduction band; ionization energy is very small, most donor atoms are ionized already at room temperature !

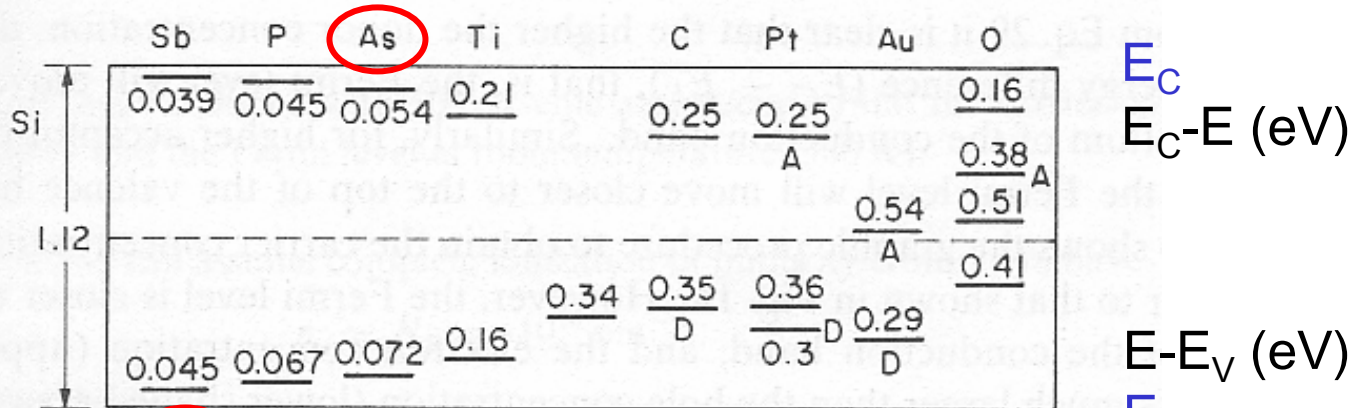
p-type Si with “*acceptor*” energy levels very close to the valence band; most acceptor atoms capture an electron, leaving a free hole already at room temperature !

Impurities and ionization energies - 1

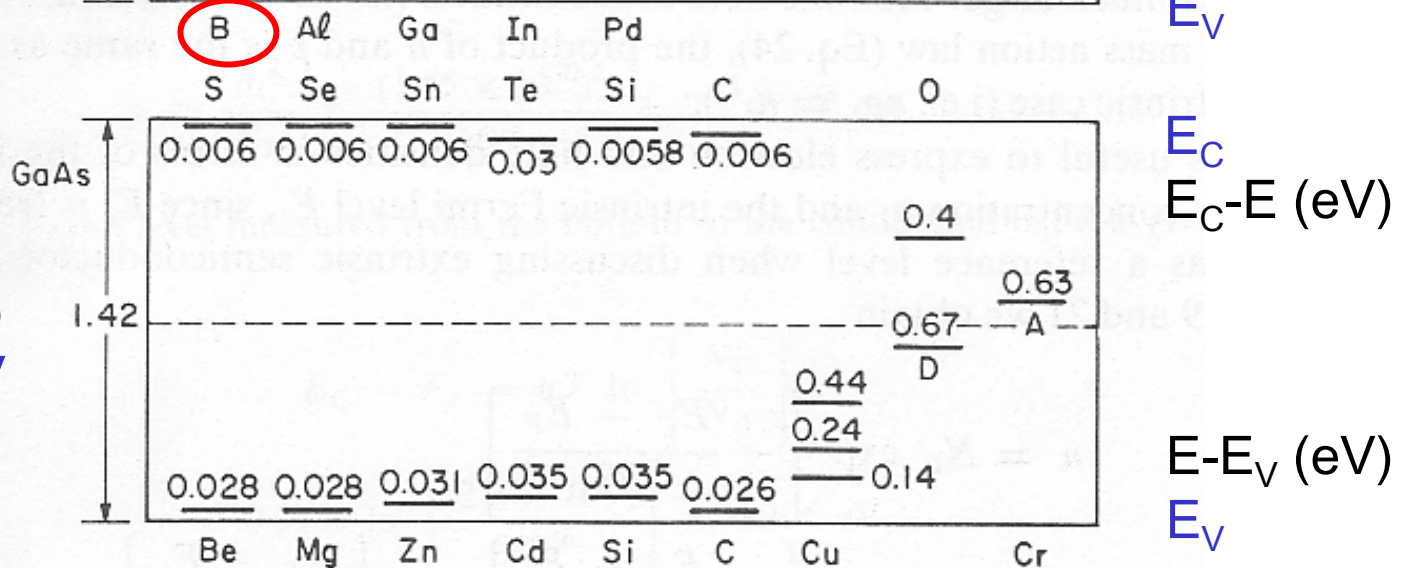
- Measured ionization energies (eV)

A = Acceptor
D = Donor

Si
energy gap
 $E_g = 1.12\text{eV}$



GaAs
energy gap
 $E_g = 1.42\text{eV}$



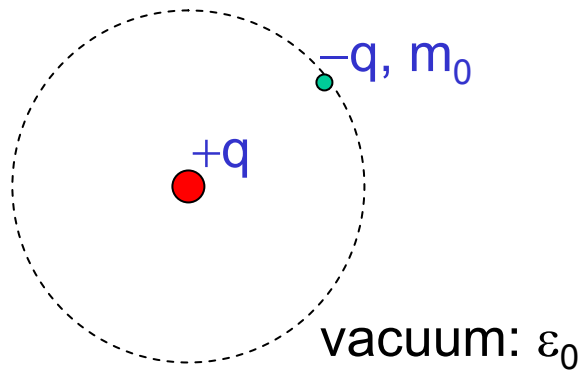
Impurities and ionization energies - 2

- Doping with donors (n-type)
 - For instance: P or As in Si
 - Level close to E_C
- Doping with acceptors (p-type)
 - For instance: B in Si
 - Level close to E_V
- Unwanted impurities
 - Many impurities (unavoidable, to some extent) contribute levels close to the center of the gap
 - Also these levels are important, as “traps” or “recombination-generation centers” (more on this later)



Impurities and ionization energies - 3

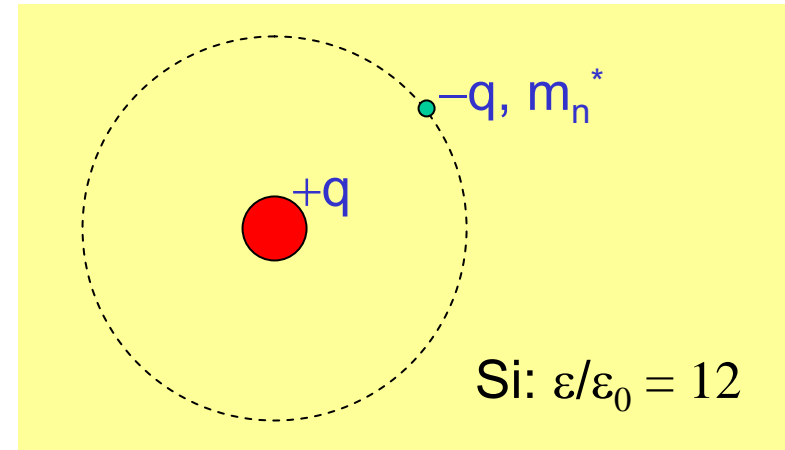
- Donor ionization energies (eV): can we understand or at least guess the order of magnitude in simple terms? Bohr model...



isolated H atom, lowest level:
Bohr model, $n=1$

$$E_n = -\frac{m_0 q^4}{8\epsilon_0^2 h^2} \frac{1}{n^2} = -13.6 \frac{1}{n^2} \text{ eV}$$

$$E_1 = -13.6 \text{ eV} \text{ ionization energy}$$



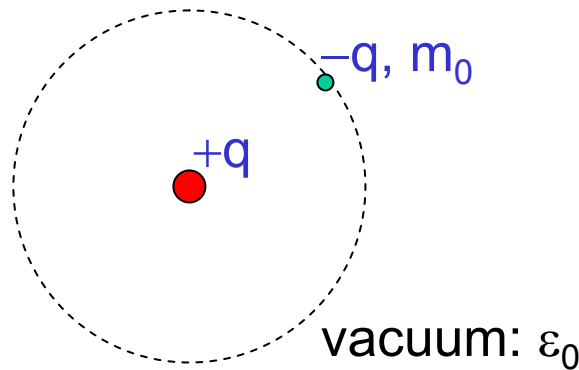
Donor atom in Si crystal:
Lowest level for the external electron

$$E_{D,n} = -\frac{m_n^* q^4}{8\epsilon^2 h^2} \frac{1}{n^2} = \left(\frac{\epsilon_0}{\epsilon}\right)^2 \left(\frac{m_n^*}{m_0}\right) E_{H,n}$$

$$E_{D,1} \approx 13.6 \text{ eV} \times \frac{1}{12^2} \times 0.9 \approx 0.085 \text{ eV} \text{ ionization energy}$$

Impurities and ionization energies - 4

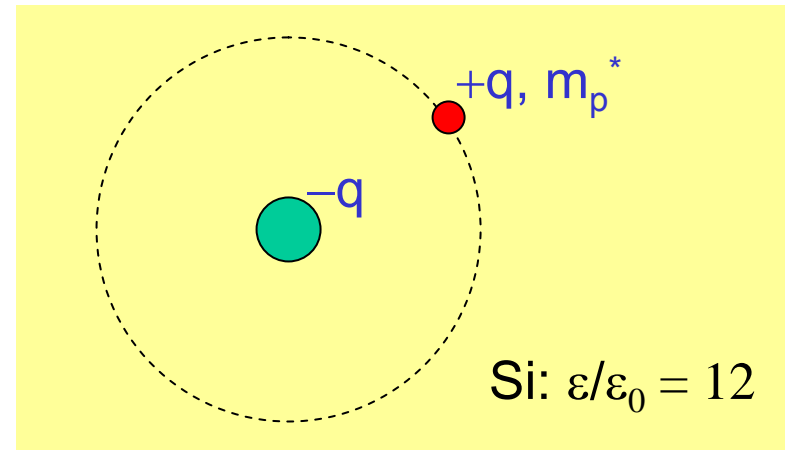
- Acceptor ionization energies (eV): similar reasoning



isolated H atom, lowest level:
Bohr model, $n=1$

$$E_n = -\frac{m_0 q^4}{8\epsilon_0^2 h^2} \frac{1}{n^2} = -13.6 \frac{1}{n^2} \text{ eV}$$

$$E_1 = -13.6 \text{ eV} \quad \text{ionization energy}$$



Acceptor atom in Si crystal:
Lowest level for the hole

$$E_{D,n} = -\frac{m_p^* q^4}{8\epsilon^2 h^2} \frac{1}{n^2} = \left(\frac{\epsilon_0}{\epsilon}\right)^2 \left(\frac{m_p^*}{m_0}\right) E_{H,n}$$

$$E_{D,1} \approx 13.6 \text{ eV} \times \frac{1}{12^2} \times 0.19 \approx 0.018 \text{ eV}$$

ionization energy

Impurities and ionization energies - 5

- The simple Bohr model for donor and acceptor ionization energies:
 - Describes the impurities in an oversimplified way (pseudo-hydrogen atoms with outer electron or hole orbiting through the semiconductor material):
 - Effective mass m_n^* , m_p^*
 - Dielectric constant ϵ
 - Gives the correct orders of magnitude for ionization energies ($E_i < 0.1\text{eV}$): OK because many semiconductor atoms are included in the Bohr orbit corresponding to the lowest level (easily checked by computing the Bohr radius)
 - Is not supposed to be able to reproduce the details !
- Small ionization energy \Rightarrow most donor/acceptor atoms are ionized at room temperature

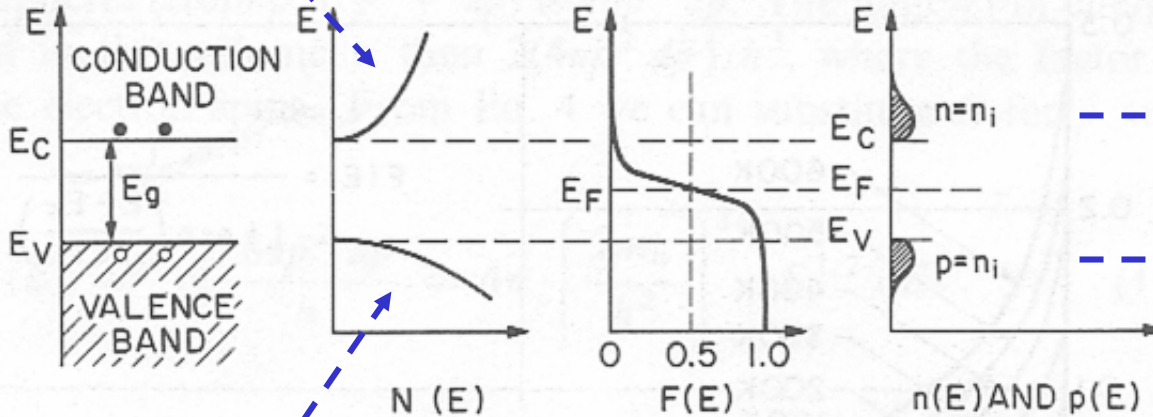


Intrinsic carrier concentration

$$g_C(E) = \frac{m_n^* \sqrt{2m_n^*(E - E_C)}}{\pi^2 \hbar^3}$$

$$F(E) \cong e^{-(E - E_F)/kT}$$

$$N_C \equiv 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2}$$



$$n \cong N_C e^{-(E_F - E_C)/kT}$$

$$p \cong N_V e^{-(E_V - E_F)/kT}$$

$$1 - F(E) \cong e^{-(E_F - E)/kT}$$

$$N_V \equiv 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2}$$

$$g_V(E) = \frac{m_p^* \sqrt{2m_p^*(E_V - E)}}{\pi^2 \hbar^3}$$



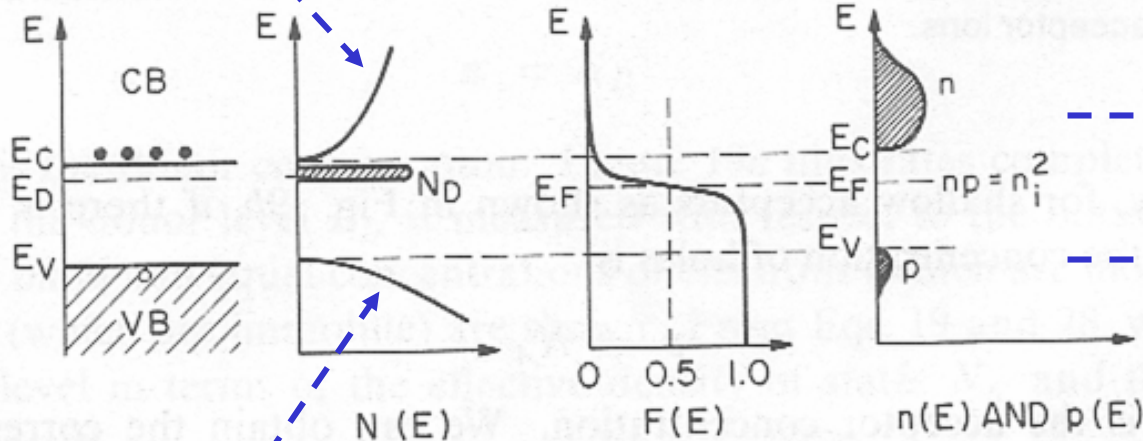
Extrinsic carrier concentration

$$g_C(E) = \frac{m_n^* \sqrt{2m_n^*(E - E_C)}}{\pi^2 \hbar^3}$$

The same ingredients...

$$F(E) \cong e^{-(E - E_F)/kT}$$

$$N_C \equiv 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2}$$



$$n \cong N_C e^{-(E_F - E_C)/kT}$$

$$p \cong N_V e^{-(E_V - E_F)/kT}$$

$$1 - F(E) \cong e^{-(E_F - E)/kT}$$

$$N_V \equiv 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2}$$

$$g_V(E) = \frac{m_p^* \sqrt{2m_p^*(E_V - E)}}{\pi^2 \hbar^3}$$

*...the same (formal) results !
But now $n \neq p$: why ??*



Carrier concentrations: intrinsic

- (approximate) equations valid for both intrinsic and extrinsic:

$$n \cong N_C e^{-(E_C - E_F)/kT} \quad N_C \equiv 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2}$$

$$p \cong N_V e^{-(E_F - E_V)/kT} \quad N_V \equiv 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2}$$

$$N_C = n_i e^{(E_C - E_i)/kT}$$

$$N_V = n_i e^{(E_i - E_V)/kT}$$

- Intrinsic case ($E_F = E_i$)

$$n = p = n_i = N_C e^{-(E_C - E_i)/kT} = N_V e^{-(E_i - E_V)/kT}$$

$$E_F = E_i = \dots \approx \frac{E_C + E_V}{2}$$

$$np = n_i^2 = N_C N_V e^{-(E_C - E_V)/kT} \Rightarrow n_i = \sqrt{N_C N_V} e^{-E_g/2kT}$$




Carrier concentrations: extrinsic

- (approximate) equations valid for both intrinsic and extrinsic:

$$n \cong N_C e^{-(E_C - E_F)/kT} \quad N_C \equiv 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2} \quad N_C = n_i e^{(E_C - E_i)/kT}$$

$$p \cong N_V e^{-(E_F - E_V)/kT} \quad N_V \equiv 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2} \quad N_V = n_i e^{(E_i - E_V)/kT}$$

- Extrinsic case: $n \neq p \Leftrightarrow E_F \neq E_i$ 

$$n = n_i e^{(E_C - E_i)/kT} e^{-(E_C - E_F)/kT} = n_i e^{(E_F - E_i)/kT}$$

$$p = n_i e^{(E_i - E_V)/kT} e^{-(E_F - E_V)/kT} = n_i e^{(E_i - E_F)/kT}$$

E_F moves away
from E_i

$$np = n_i^2$$

$$n\text{-type: } n \approx N_D \quad p \approx n_i^2 / N_D$$

$$p\text{-type: } p \approx N_A \quad n \approx n_i^2 / N_A$$

approximate
for
complete
ionization



Fermi level for complete ionization

- Complete ionization of donors:

$$n = N_C e^{-(E_C - E_F)/kT} \approx N_D \Rightarrow \frac{N_C}{N_D} = e^{(E_C - E_F)/kT}$$

$$\Rightarrow E_C - E_F = kT \ln \left(\frac{N_C}{N_D} \right)$$

- Complete ionization of acceptors:

$$p = N_V e^{-(E_F - E_V)/kT} \approx N_A \Rightarrow \frac{N_V}{N_A} = e^{(E_C - E_F)/kT}$$

$$\Rightarrow E_F - E_V = kT \ln \left(\frac{N_V}{N_A} \right)$$



Concentrations and E_F : an example

- A silicon ingot is doped with As ($N_D \approx 10^{16}$ atoms/cm³). Find the carrier concentration and the Fermi level at room temperature ($T=300\text{K}$)

Assuming complete ionization of donors:

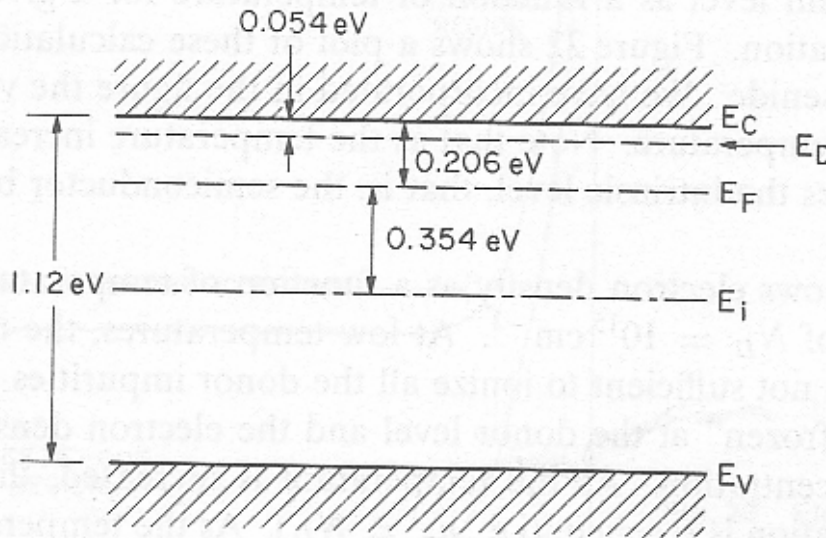


Fig. 21 Band diagram showing Fermi level E_F and intrinsic Fermi level E_i .

$$n \approx N_D = 10^{16} \text{ cm}^{-3}$$

$$\begin{aligned} n_i &= N_C e^{-(E_C - E_i)/kT} \approx \\ &\approx (2.8 \times 10^{19}) \times (5.2 \times 10^{-10}) \approx \\ &\approx 1.45 \times 10^{10} \text{ cm}^{-3} \end{aligned}$$

$$\begin{aligned} p &\approx n_i^2 / N_D = \frac{(1.45 \times 10^{10})^2}{10^{16}} = \\ &= 2.1 \times 10^4 \text{ cm}^{-3} \end{aligned}$$

$$\begin{aligned} E_C - E_F &= kT \ln\left(\frac{N_C}{N_D}\right) = 0.0259 \ln\left(\frac{2.8 \times 10^{19}}{10^{16}}\right) = \\ &= 0.206 \text{ eV} \end{aligned}$$

$$\begin{aligned} n &= n_i e^{(E_F - E_i)/kT} \Rightarrow E_F - E_i = kT \ln\left(\frac{n}{n_i}\right) \\ E_F - E_i &= 0.0259 \ln\left(\frac{10^{16}}{1.45 \times 10^{10}}\right) = 0.354 \text{ eV} \end{aligned}$$



Fermi level: general case

- Both donor and acceptor impurities present simultaneously
 - Concentrations: N_D and N_A respectively
- starting point: overall *charge neutrality* and *mass action law*

$$n + N_A = p + N_D \quad np = n_i^2$$

n-type: $N_D > N_A$

$$n_n = \frac{1}{2} \left[N_D - N_A + \sqrt{(N_D - N_A)^2 + 4n_i^2} \right]$$
$$p_n = n_i^2 / n_n$$

if $|N_D - N_A| \gg n_i$

$$n_n \approx N_D - N_A$$

p-type: $N_A > N_D$

$$p_p = \frac{1}{2} \left[N_A - N_D + \sqrt{(N_A - N_D)^2 + 4n_i^2} \right]$$
$$n_p = n_i^2 / p_p$$

if $|N_D - N_A| \gg n_i$

$$p_p \approx N_A - N_D$$



Extrinsic Fermi level vs temperature

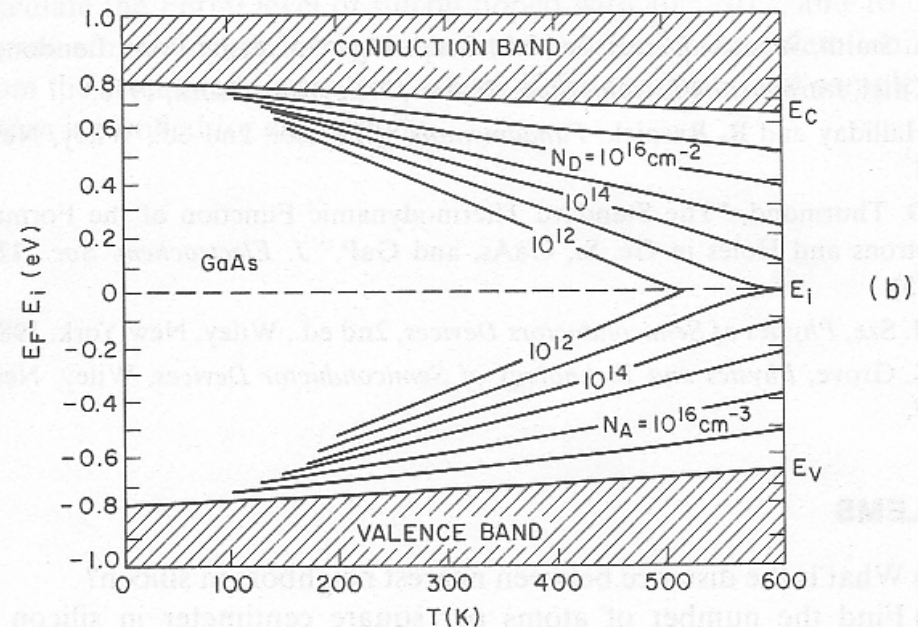
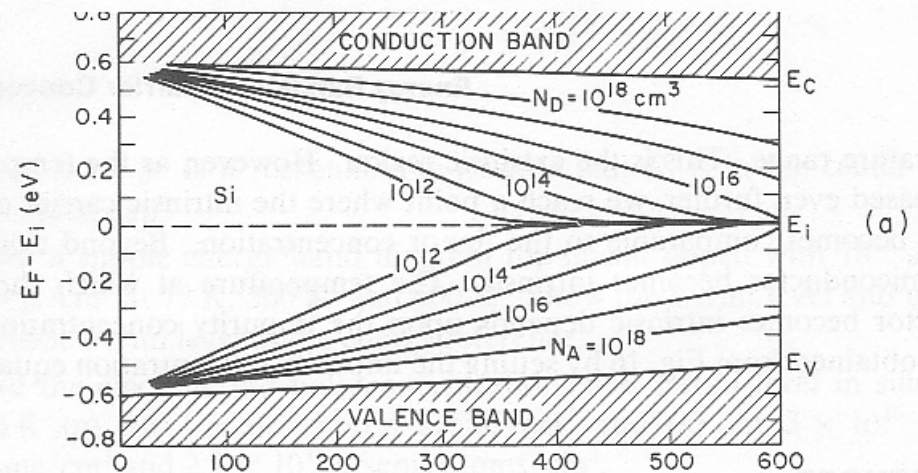
- Fermi level computation in the general case, taking T into account:

- from N_D and N_A compute n , p
- from n , p extract E_F

$$n = n_i e^{(E_F - E_i)/kT} \Rightarrow E_F = \dots$$

$$p = n_i e^{(E_i - E_F)/kT} \Rightarrow E_F = \dots$$

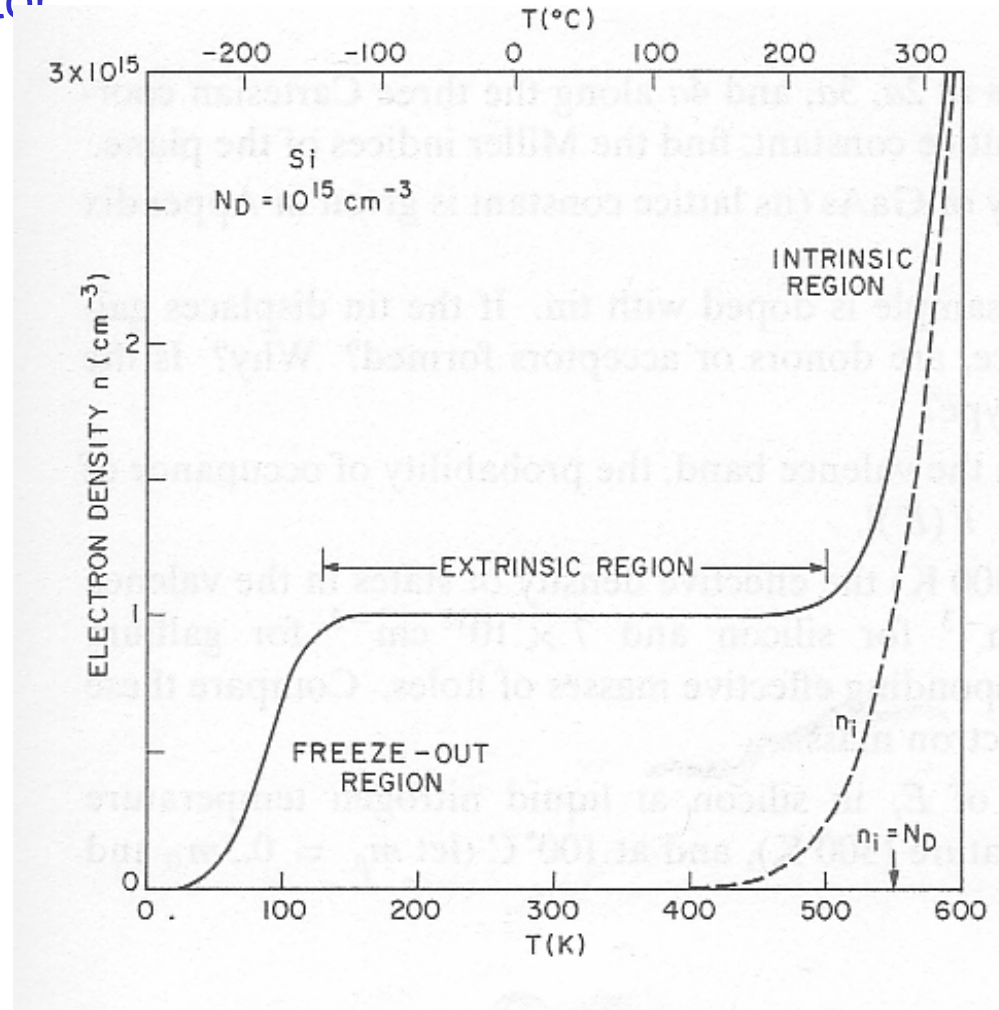
- n_i increases with T !
- Low T: extrinsic behaviour
- High T: intrinsic behaviour



Electron density vs temperature

- Another point of view: carrier density in n-type semiconductor

- Very low T:
 - “freeze-out” region
 - donors not ionized
- Medium T:
 - “extrinsic” region
 - $n \approx N_D$
- High T:
 - “intrinsic” region
 - $n \approx n_i$



Lecture 3 - summary

- The “mass action law” ($np = n_i^2$) is always valid
- The intrinsic concentration n_i increases with T
- We found relations between n , p , n_i and E_F
- In the intrinsic case $n = p = n_i$
- We have learned how to compute n , p , and E_F in the general extrinsic case (depending on N_D , N_A)
- Intrinsic/extrinsic behaviour depends on T !



Lecture 3 – Items to be understood...

- Some items that require a deeper explanation:
 - Bohr model
 - Density of states
 - Fermi distribution function
 - Energy band model
 - Donors and acceptor energy levels



Lecture 3 - exercises

- **Exercise 3.1:** A silicon sample at $T=300\text{K}$ contains an acceptor impurity concentration of $N_A=10^{16}\text{ cm}^{-3}$. Determine the concentration of donor impurity atoms that must be added so that the silicon is n-type and the Fermi energy is 0.20 eV below the conduction band edge.
- **Exercise 3.2:** Find the electron and hole concentrations and Fermi level in silicon at 300K (a) for 1×10^{15} boron atoms/ cm^3 and (b) for 3×10^{16} boron atoms / cm^3 together with 2.9×10^{16} arsenic atoms/ cm^3 .
- **Exercise 3.3:** Calculate the Fermi level of silicon doped with 10^{15} , 10^{17} and 10^{19} phosphorus atoms/ cm^3 , assuming complete ionization. From the calculated Fermi level, check if the assumption of complete ionization is justified for each doping. Assume that the ionized donors density is given by $N_D^+ = N_D(1-F(E_D))$.



Backup slides